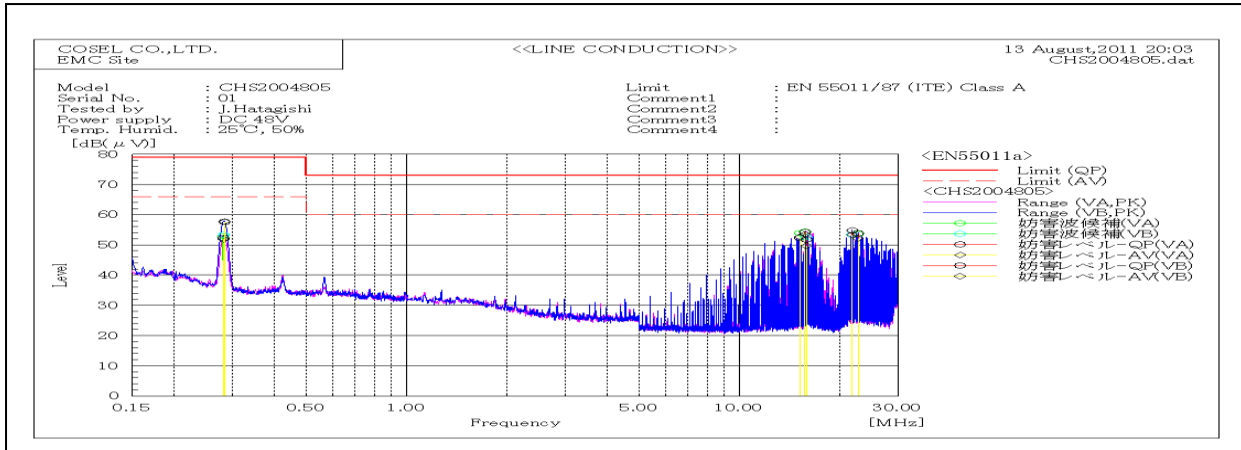
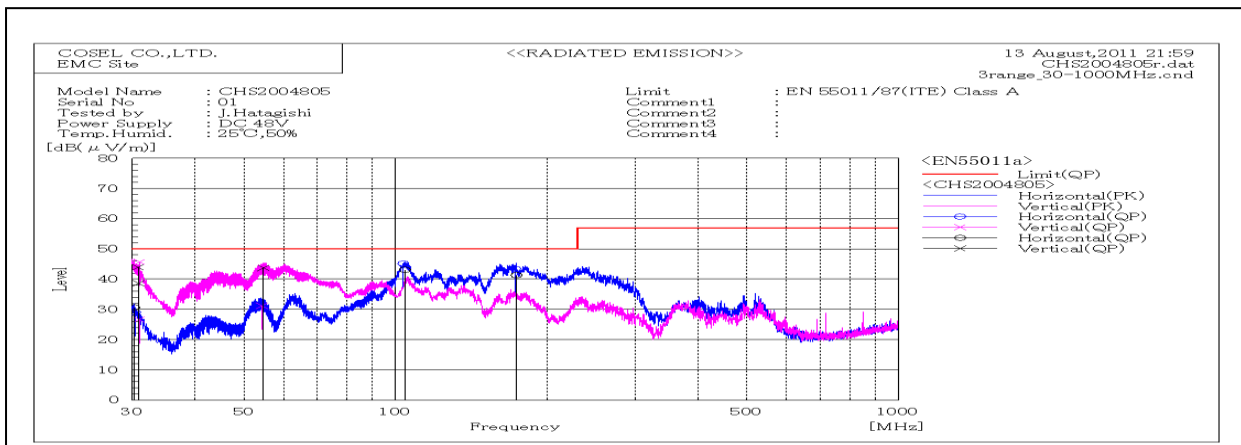


DATA SHEET		Date	13-Aug-11
Model	CHS2004805	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	J.Hatagishi



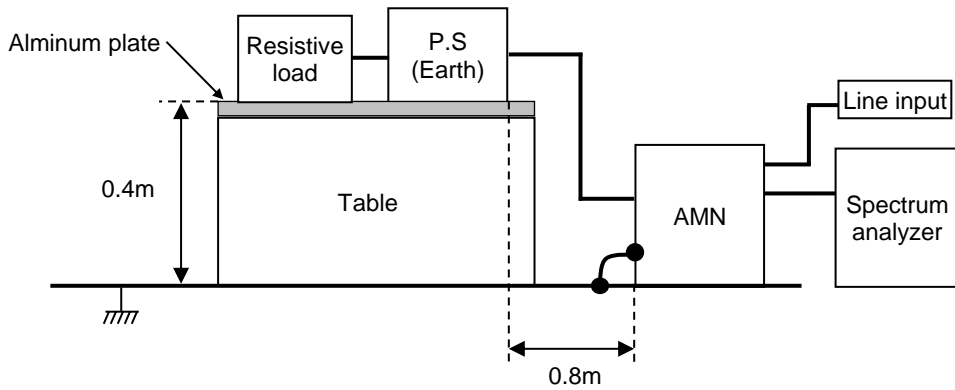
Frequency MHz	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail
		QP	AV		QP	AV	QP	AV	QP	AV	
0.28191	VA	42.3	41.9	10	52.3	51.9	79	66	26.7	14.1	Pass
0.28391	VB	47.6	47.7	10	57.6	57.7	79	66	21.4	8.3	Pass
15.17	VA	41.7	41.9	10.7	52.4	52.6	73	60	20.6	7.4	Pass
15.7404	VA	43.5	42.7	10.8	54.3	53.5	73	60	18.7	6.5	Pass
15.87695	VB	41.1	39.1	10.7	51.8	49.8	73	60	21.2	10.2	Pass
21.8422	VB	43.9	42.4	10.9	54.8	53.3	73	60	18.2	6.7	Pass
22.69345	VA	42.8	41.1	11	53.8	52.1	73	60	19.2	7.9	Pass



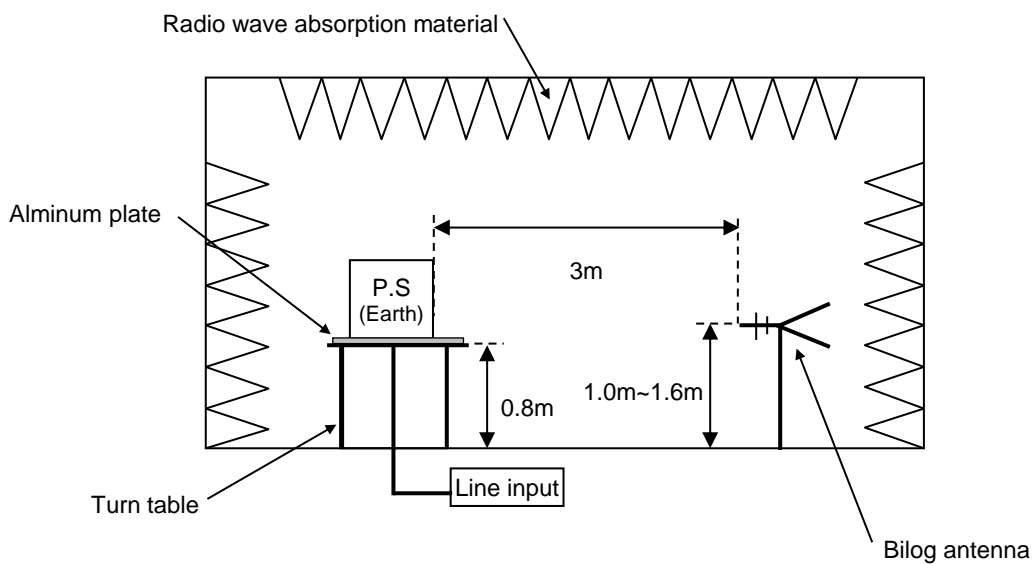
Frequency MHz	Polarization	Stability	Reading	Space Loss dB	Level	Limit	Margin dB	Pass/Fail	Height cm	Angle deg
			dB(uV)		dB(mW)	dB(mW)				
			QP		QP	QP				
30.258	H	Stable	44.1	-13.5	30.6	50	19.4	Pass	120	71
30.903	V	Stable	52.4	-13.8	38.6	50	11.4	Pass	136	231
30.813	V	Stable	57.7	-13.8	43.9	50	6.1	Pass	104	255
54.707	V	Stable	69.2	-25.5	43.7	50	6.3	Pass	105	294
104.503	H	Stable	64.1	-21	43.1	50	6.9	Pass	158	134
173.998	H	Stable	63.5	-22.2	41.3	50	8.7	Pass	158	107

DATA SHEET		Date	13-Aug-11
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	J.Hatagishi

1. Line conduction



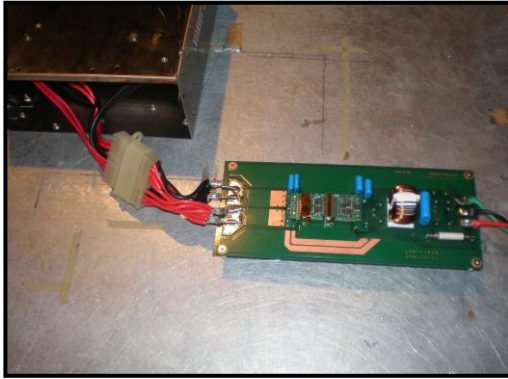
2. Radiated emission



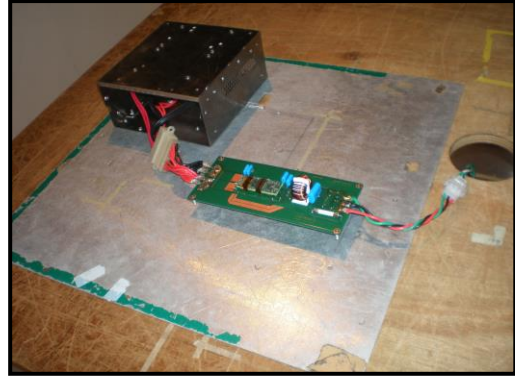
Test : EMI
 Model Name : CHS200 Series

○ Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○ Testing circuitry

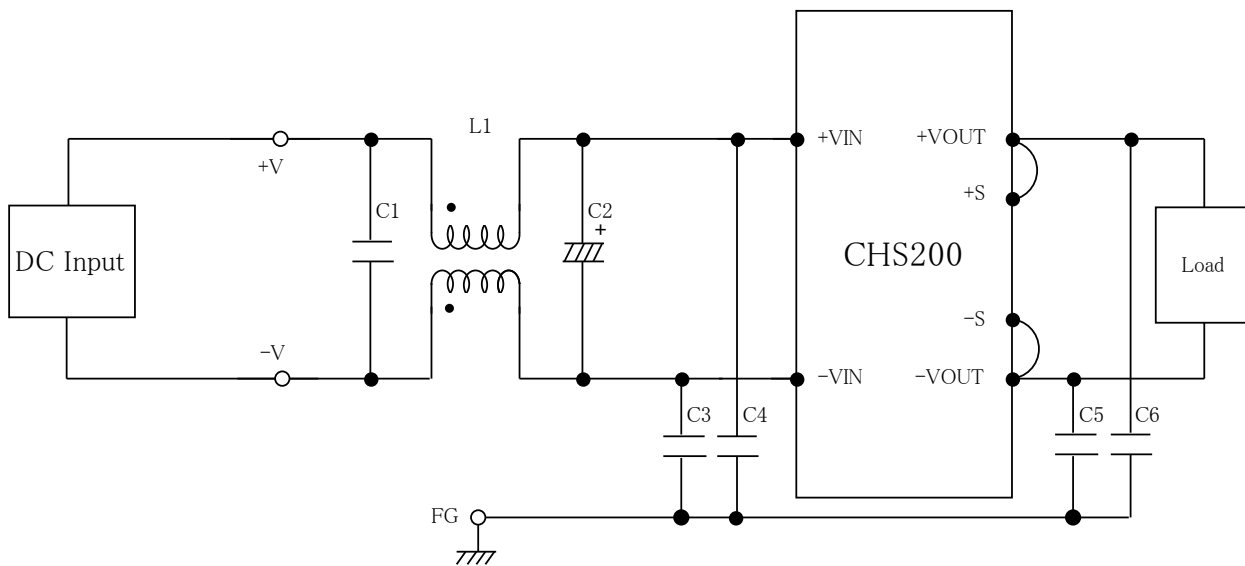


Fig.1 Testing circuitry

- L1 : 1mH SC-10-10J (TOKIN)
- C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
- C2 : 100V 100 μ F PWseries (nichicon)
- C3,C4 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
- C5,C6 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)